

IN THE CLAIMS

Please amend the claims to read as follows:

Listing of Claims

1. (Original) A semiconductor integrated circuit comprising:  
a memory operating on a first clock,  
a first test pattern generation section, operating on a  
second clock having half the frequency of said first clock, for  
generating first test data,  
a second test pattern generation section, operating on a  
third clock, the inverted clock of said second clock, for  
generating second test data, and  
a test data selection section for selectively outputting  
either said first or second test data being output from said  
first test pattern generation section or said second test pattern  
generation section, respectively, depending on either the signal  
value of said second clock or the signal value of said third  
clock, thereby inputting the selected test data to said memory as  
third test data.

2. (Original) A semiconductor integrated circuit comprising:  
a memory operating on a first clock,

a first test pattern generation section, operating on a second clock having half the frequency of said first clock, for generating first test data,

a second test pattern generation section, operating on said second clock, for generating second test data, and

a test data selection section for selectively outputting either said first or second test data being output from said first test pattern generation section or said second test pattern generation section, respectively, depending on the signal value of said second clock, thereby inputting the selected test data to said memory as third test data.

3. (Original) A semiconductor integrated circuit comprising:  
a memory operating on a first clock,  
a test pattern generation section, operating on a second clock having half the frequency of said first clock, for generating first test data,  
an LSB0 processing section for generating second test data by adding numeric value 0 to said first test data generated by said test pattern generation section as the least significant bit thereof,  
an LSB1 processing section for generating third test data by adding numeric value 1 to said first test data generated by said

test pattern generation section as the least significant bit thereof, and

a test data selection section for selectively outputting either said second or third test data being output from said LSB0 processing section or said LSB1 processing section, respectively, depending on the signal value of said second clock, thereby inputting the selected test data to said memory as fourth test data.

4. (Original) A semiconductor integrated circuit in accordance with claim 3, wherein a delay circuit for generating a delay clock obtained by delaying said second clock and for supplying said delay clock to said test data selection section is provided.

5. (Original) A semiconductor integrated circuit comprising:

a memory operating on a first clock,  
a test pattern generation section, operating on a second clock having half the frequency of said first clock, for generating first test data,  
an LSB0 processing section for generating second test data by adding numeric value 0 to said first test data generated by

said test pattern generation section as the least significant bit thereof,

an LSB1 processing section for generating third test data by adding numeric value 1 to said first test data generated by said test pattern generation section as the least significant bit thereof,

a clock selection section capable of selecting either said second clock or the inverted clock of said second clock, and

a test data selection section for selectively outputting either said second or third test data being output from said LSB0 processing section or said LSB1 processing section, respectively, depending on the output of said clock selection section, thereby inputting the selected test data to said memory as fourth test data.

6. (Original) A semiconductor integrated circuit comprising:

a memory operating on a first clock,  
a memory device for capturing first output data being output from said memory in synchronization with said first clock, depending on a second clock having half the frequency of said first clock, and

an expected value comparison section, operating on said second clock, for respectively comparing second output data being output from said memory device and third output data being output from said memory immediately after the output of said first output data with a predetermined expected value.

7. (Original) A semiconductor integrated circuit comprising:

a double data rate memory operating on a first clock, a first test pattern generation section, operating on a second clock having the same frequency as that of said first clock, for generating first test data,

a second test pattern generation section, operating on a third clock, the inverted clock of said second clock, for generating second test data, and

a test data selection section for selectively outputting either said first or second test data being output from said first test pattern generation section or said second test pattern generation section, respectively, depending on either the signal value of said second clock or the signal value of said third clock, thereby inputting the selected test data to said double data rate memory as third test data.

8. (Original) A semiconductor integrated circuit comprising:

a double data rate memory operating on a first clock,  
a first test pattern generation section, operating on a second clock having the same frequency of that of said first clock, for generating first test data,  
a second test pattern generation section, operating on said second clock, for generating second test data, and  
a test data selection section for selectively outputting either said first or second test data being output from said first test pattern generation section or said second test pattern generation section, respectively, depending on the signal value of said second clock, thereby inputting the selected test data to said double data rate memory as third test data.

9. (Original) A semiconductor integrated circuit comprising:

a double data rate memory operating on a first clock,  
a test pattern generation section, operating on a second clock having the same frequency as that of said first clock, for generating first test data,

an LSB0 processing section for generating second test data by adding numeric value 0 to said first test data generated by said test pattern generation section as the least significant bit thereof,

an LSB1 processing section for generating third test data by adding numeric value 1 to said first test data generated by said test pattern generation section as the least significant bit thereof, and

a test data selection section for selectively outputting either said second or third test data being output from said LSB0 processing section or said LSB1 processing section, respectively, depending on the signal value of said second clock, thereby inputting the selected test data to said double data rate memory as fourth test data.

10. (Original) A semiconductor integrated circuit in accordance with claim 9, wherein a delay circuit for generating a delay clock obtained by delaying said second clock and for supplying said delay clock to said test data selection section is provided.

11. (Original) A semiconductor integrated circuit comprising:

a double data rate memory operating on a first clock,  
a test pattern generation section, operating on a second  
clock having the same frequency as that of said first clock, for  
generating first test data,

an LSB0 processing section for generating second test data  
by adding numeric value 0 to said first test data generated by  
said test pattern generation section as the least significant bit  
thereof,

an LSB1 processing section for generating third test data by  
adding numeric value 1 to said first test data generated by said  
test pattern generation section as the least significant bit  
thereof,

a clock selection section capable of selecting either said  
second clock or the inverted clock of said second clock, and

a test data selection section for selectively outputting  
either said second or third test data being output from said LSB0  
processing section or said LSB1 processing section, respectively,  
depending on the output of said clock selection section, thereby  
inputting the selected test data to said double data rate memory  
as fourth test data.

12. (Original) A semiconductor integrated circuit  
comprising:

a double data rate memory operating on a first clock,  
a memory device for capturing first output data being output  
from said double data rate memory in synchronization with said  
first clock, depending on a second clock having the same  
frequency as that of said first clock, and  
an expected value comparison section, operating on said  
second clock, for respectively comparing second output data being  
output from said memory device and third output data being output  
from said double data rate memory immediately after the output of  
said first output data with a predetermined expected value.

13. (Original) A method of testing a memory operating on a  
first clock, comprising the steps of generating first test data  
depending on a second clock having half the frequency of said  
first clock, generating second test data depending on a third  
clock, the inverted clock of said second clock, selecting either  
said first or second test data depending on either the signal  
value of said second clock or the signal value of said third  
clock, and inputting the selected test data to said memory as  
third test data.

14. (Original) A method of testing a memory operating on a  
first clock, comprising the steps of generating first test data

depending on a second clock having half the frequency of said first clock, generating second test data by adding numeric value 0 to said first test data as the least significant bit thereof, generating third test data by adding numeric value 1 to said first test data as the least significant bit thereof, selecting either said second or third test data depending on the signal value of said second clock, and inputting the selected test data to said memory.

15. (Original) A method of testing a memory operating on a first clock, comprising the steps of holding first data being output from said memory in synchronization with said first clock as second data depending on a second clock having half the frequency of said first clock, and respectively comparing said second data and third data being output in synchronization with said first clock from said memory immediately after the output of said first data with a predetermined expected value depending on said second clock.

16. (Original) A method of testing a double data rate memory operating on a first clock, comprising the steps of generating first test data depending on a second clock having the same frequency as that of said first clock, generating second

test data depending on a third clock, the inverted clock of said second clock, selecting either said first or second test data depending on either the signal value of said second clock or the signal value of said third clock, and inputting the selected test data to said double data rate memory as third test data.

17. (Original) A method of testing a double data rate memory operating on a first clock, comprising the steps of generating first test data depending on a second clock having the same frequency as that of said first clock, generating second test data by adding numeric value 0 to said first test data as the least significant bit thereof, generating third test data by adding numeric value 1 to said first test data as the least significant bit thereof, selecting either said second or third test data depending on the signal value of said second clock, and inputting the selected test data to said double data rate memory.

18. (Original) A method of testing a double data rate memory operating on a first clock, comprising the steps of holding first data being output from said double data rate memory in synchronization with said first clock as second data depending on a second clock having the same frequency as that of said first clock, and respectively comparing said second data and third data

being output in synchronization with said first clock from said double data rate memory immediately after the output of said first data with a predetermined expected value depending on said second clock.

19. (Original) A semiconductor integrated circuit in accordance with claim 1, wherein a delay circuit for generating a delay clock obtained by delaying said second clock and for supplying said delay clock to said test data selection section is provided.

20. (Original) A semiconductor integrated circuit in accordance with claim 2, wherein a delay circuit for generating a delay clock obtained by delaying said second clock and for supplying said delay clock to said test data selection section is provided.

21. (Original) A semiconductor integrated circuit in accordance with claim 7, wherein a delay circuit for generating a delay clock obtained by delaying said second clock and for supplying said delay clock to said test data selection section is provided.

22. (Original) A semiconductor integrated circuit in accordance with claim 8, wherein a delay circuit for generating a delay clock obtained by delaying said second clock and for supplying said delay clock to said test data selection section is provided.

23. (Original) A semiconductor integrated circuit comprising:

    a memory operating on a first clock,  
    a first test pattern generation section, operating on a second clock having half the frequency of said first clock, for generating first test data,

    a second test pattern generation section, operating on a third clock, the inverted clock of said second clock, for generating second test data,

    a clock selection section capable of selecting either said second clock or the inverted clock of said second clock, and

    a test data selection section for selectively outputting either said first or second test data being output from said first test pattern generation section or said second test pattern generation section, respectively, depending on the output of said clock selection section, thereby inputting the selected test data to said memory as third test data.

24. (Original) A semiconductor integrated circuit comprising:

    a memory operating on a first clock,

    a first test pattern generation section, operating on a second clock having half the frequency of said first clock, for generating first test data,

    a second test pattern generation section, operating on said second clock, for generating second test data,

    a clock selection section capable of selecting either said second clock or the inverted clock of said second clock, and

    a test data selection section for selectively outputting either said first or second test data being output from said first test pattern generation section or said second test pattern generation section, respectively, depending on the output of said clock selection section, thereby inputting the selected test data to said memory as third test data.

25. (Original) A semiconductor integrated circuit comprising:

    a double data rate memory operating on a first clock,

    a first test pattern generation section, operating on a second clock having the same frequency as that of said first clock, for generating first test data,

a second test pattern generation section, operating on a third clock, the inverted clock of said second clock, for generating second test data,

a clock selection section capable of selecting either said second clock or the inverted clock of said second clock, and

a test data selection section for selectively outputting either said first or second test data being output from said first test pattern generation section or said second test pattern generation section, respectively, depending on the output of said clock selection section, thereby inputting the selected test data to said double data rate memory as third test data.

26. (Original) A semiconductor integrated circuit comprising:

a double data rate memory operating on a first clock,

a first test pattern generation section, operating on a second clock having the same frequency as that of said first clock, for generating first test data,

a second test pattern generation section, operating on said second clock, for generating second test data,

a clock selection section capable of selecting either said second clock or the inverted clock of said second clock, and

a test data selection section for selectively outputting either said first or second test data being output from said first test pattern generation section or said second test pattern generation section, respectively, depending on the output of said clock selection section, thereby inputting the selected test data to said double data rate memory as third test data.

27. (New) A method of testing a memory operating on a first clock, comprising the steps of generating first test data depending on a second clock having half the frequency of said first clock, generating second test data depending on said second clock, selecting either said first or second test data depending on the signal value of said second clock, and inputting the selected test data to said memory as third test data.

28. (New) A method of testing a double data rate memory operating on a first clock, comprising the steps of generating first test data depending on a second clock having the same frequency as that of said first clock, generating second test data depending on said second clock, selecting either said first or second test data depending on the signal value of said second clock, and inputting the selected test data to said double data rate memory as third test data.